Suntac ELECTRONIC CORP

IRF10N40

POWER MOSFET

GENERAL DESCRIPTION

This high voltage MOSFET uses an advanced termination scheme to provide enhanced voltage-blocking capability without degrading performance over time. In addition, this advanced MOSFET is designed to withstand high energy in avalanche and commutation modes. The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for high voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional and safety margin against unexpected voltage transients.
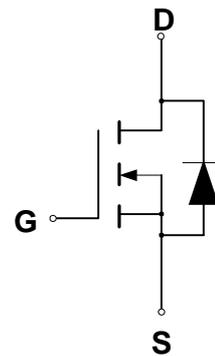
FEATURES

◆ Robust High Voltage Termination
◆ Avalanche Energy Specified
◆ Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
◆ Diode is Characterized for Use in Bridge Circuits
◆ I_{DSS} and V_{DS}(on) Specified at Elevated Temperature

PIN CONFIGURATION

TO-220
Top View
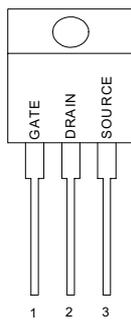
SYMBOL

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain to Current — Continuous	I_D	10	A
— Pulsed	I_{DM}	40	
Gate-to-Source Voltage — Continue	V_{GS}	±20	V
— Non-repetitive	V_{GSM}	±40	V
Total Power Dissipation	P_D	125	W
Derate above 25℃		1.0	W/℃
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to 150	℃
Single Pulse Drain-to-Source Avalanche Energy — T_J = 25℃ (V_{DD} = 100V, V_{GS} = 10V, I_L = 10A, L = 6mH, R_G = 25Ω)	E_{AS}	300	mJ
Thermal Resistance — Junction to Case	$θ_{JC}$	1.7	℃/W
— Junction to Ambient	$θ_{JA}$	62.5	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	T_L	260	℃

ORDERING INFORMATION

Part Number	Package
IRF10N40	TO-220

ELECTRICAL CHARACTERISTICS

Unless otherwise specified, T_J = 25℃.

Characteristic		Symbol	Min	Typ	Max	Units
Drain-Source Breakdown Voltage (V_{GS} = 0 V, I_D = 250 μA)		$V_{(BR)DSS}$	400			V
Drain-Source Leakage Current (V_{DS} = 400 V, V_{GS} = 0 V) (V_{DS} = 400 V, V_{GS} = 0 V, T_J = 125℃)		I_{DSS}			0.25 / 1.0	mA
Gate-Source Leakage Current-Forward (V_{gsf} = 20 V, V_{DS} = 0 V)		I_{GSSF}			100	nA
Gate-Source Leakage Current-Reverse (V_{gsr} = 20 V, V_{DS} = 0 V)		I_{GSSR}			-100	nA
Gate Threshold Voltage (V_{DS} = V_{GS}, I_D = 250 μA)		$V_{GS(th)}$	2.0		4.0	V
Static Drain-Source On-Resistance (V_{GS} = 10 V, I_D = 5.0A) *		$R_{DS(on)}$		0.4	0.55	Ω
Drain-Source On-Voltage (V_{GS} = 10 V) (I_D = 5.0 A)		$V_{DS(on)}$			6.0	V
Forward Transconductance (V_{DS} = 50 V, I_D = 5.0A) *		g_{FS}		4.0		mhos
Input Capacitance	(V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 MHz)	C_{iss}		1570		pF
Output Capacitance		C_{oss}		230		pF
Reverse Transfer Capacitance		C_{rss}		55		pF
Turn-On Delay Time	(V_{DD} = 200 V, I_D = 10.0 A, V_{GS} = 10 V, R_G = 10Ω) *	$t_{d(on)}$		25		ns
Rise Time		t_r		37		ns
Turn-Off Delay Time		$t_{d(off)}$		75		ns
Fall Time		t_f		31		ns
Total Gate Charge	(V_{DS} = 320 V, I_D = 10.0 A, V_{GS} = 10 V)*	Q_g		46	63	nC
Gate-Source Charge		Q_{gs}		10		nC
Gate-Drain Charge		Q_{gd}		23		nC
Internal Drain Inductance (Measured from the drain lead 0.25" from package to center of die)		L_D		4.5		nH
Internal Drain Inductance (Measured from the source lead 0.25" from package to source bond pad)		L_S		7.5		nH
SOURCE-DRAIN DIODE CHARACTERISTICS						
Forward On-Voltage(1)	(I_S = 10.0 A, V_{GS} = 0 V, d_{IS}/d_t = 100A/μs)	V_{SD}			2.0	V
Forward Turn-On Time		t_{on}		**		ns
Reverse Recovery Time		t_{rr}		250		ns

* Pulse Test: Pulse Width ≦300μs, Duty Cycle ≦2%

** Negligible, Dominated by circuit inductance

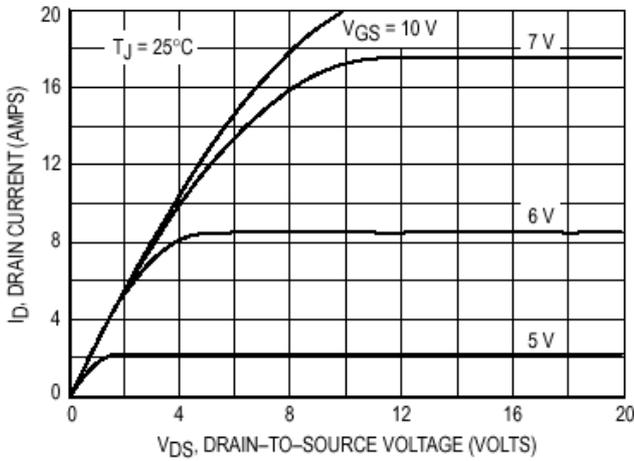## TYPICAL ELECTRICAL CHARACTERISTICS
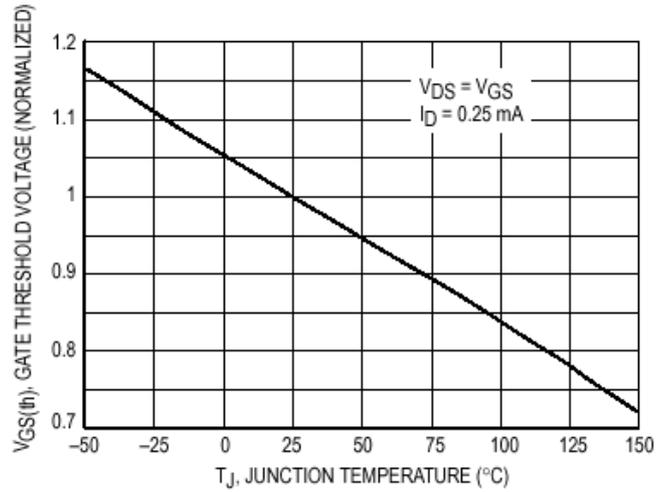
Figure 1. On–Region Characteristics

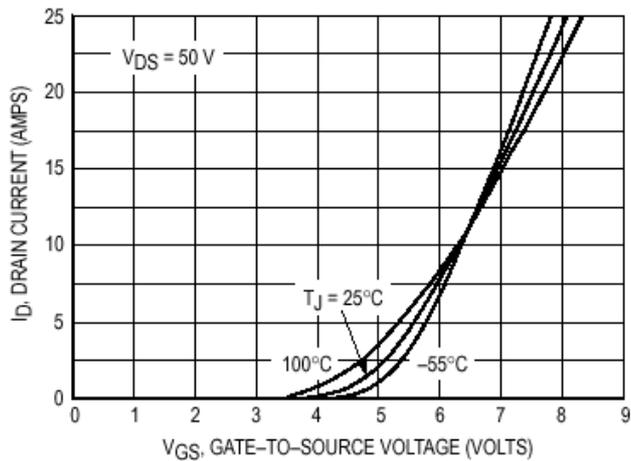Figure 2. Gate–Threshold Voltage Variation With Temperature
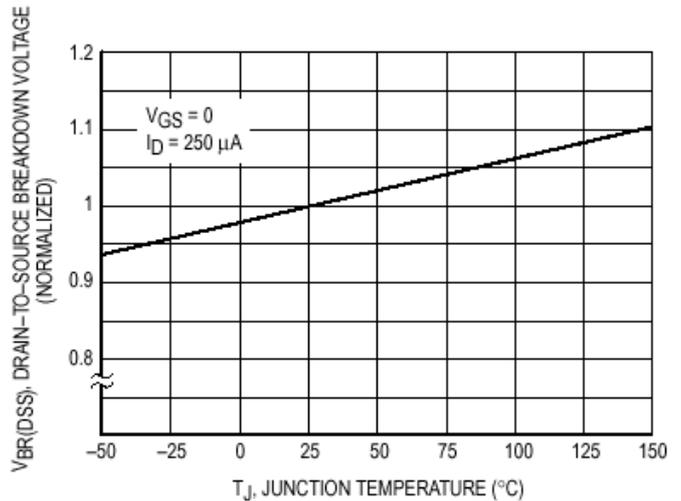
Figure 3. Transfer Characteristics

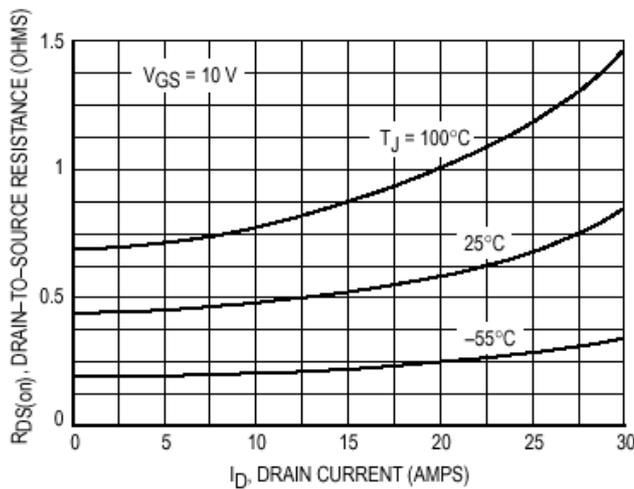Figure 4. Breakdown Voltage Variation With Temperature
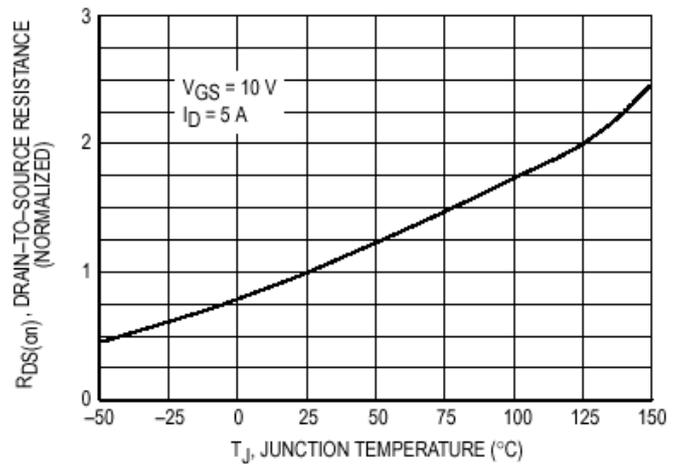
Figure 5. On–Resistance versus Drain Current

Figure 6. On–Resistance Variation With Temperature